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Understanding [Embedded - CPLDs \(Complex Programmable Logic Devices\)](#)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs

Details

Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	5.5 ns
Voltage Supply - Internal	4.75V ~ 5.25V
Number of Logic Elements/Blocks	-
Number of Macrocells	128
Number of Gates	-
Number of I/O	64
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/m4a5-128-64-55vc

GENERAL DESCRIPTION

The ispMACH™ 4A family from Lattice offers an exceptionally flexible architecture and delivers a superior Complex Programmable Logic Device (CPLD) solution of easy-to-use silicon products and software tools. The overall benefits for users are a guaranteed and predictable CPLD solution, faster time-to-market, greater flexibility and lower cost. The ispMACH 4A devices offer densities ranging from 32 to 512 macrocells with 100% utilization and 100% pin-out retention. The ispMACH 4A families offer 5-V (M4A5-xxx) and 3.3-V (M4A3-xxx) operation.

ispMACH 4A products are 5-V or 3.3-V in-system programmable through the JTAG (IEEE Std. 1149.1) interface. JTAG boundary scan testing also allows product testability on automated test equipment for device connectivity.

All ispMACH 4A family members deliver First-Time-Fit and easy system integration with pin-out retention after any design change and refit. For both 3.3-V and 5-V operation, ispMACH 4A products can deliver guaranteed fixed timing as fast as 5.0 ns t_{PD} and 182 MHz f_{CNT} through the SpeedLocking feature when using up to 20 product terms per output (Table 2).

Table 2. ispMACH 4A Speed Grades

Device	Speed Grade							
	-5	-55	-6	-65	-7	-10	-12	-14
M4A3-32	C				C, I	C, I	I	
M4A5-32								
M4A3-64/32		C			C, I	C, I	I	
M4A5-64/32								
M4A3-64/64		C			C, I	C, I	I	
M4A3-96		C			C, I	C, I	I	
M4A5-96								
M4A3-128		C			C, I	C, I	I	
M4A5-128								
M4A3-192			C		C, I	C, I	I	
M4A5-192								
M4A3-256/128		C		C	C, I	C, I	I	
M4A5-256/128				C	C	C, I	I	
M4A3-256/192					C	C, I	I	
M4A3-256/160								
M4A3-384				C		C, I	C, I	I
M4A3-512					C	C, I	C, I	I

Note:

1. C = Commercial, I = Industrial

Macrocell

The macrocell consists of a storage element, routing resources, a clock multiplexer, and initialization control. The macrocell has two fundamental modes: synchronous and asynchronous (Figure 5). The mode chosen only affects clocking and initialization in the macrocell.

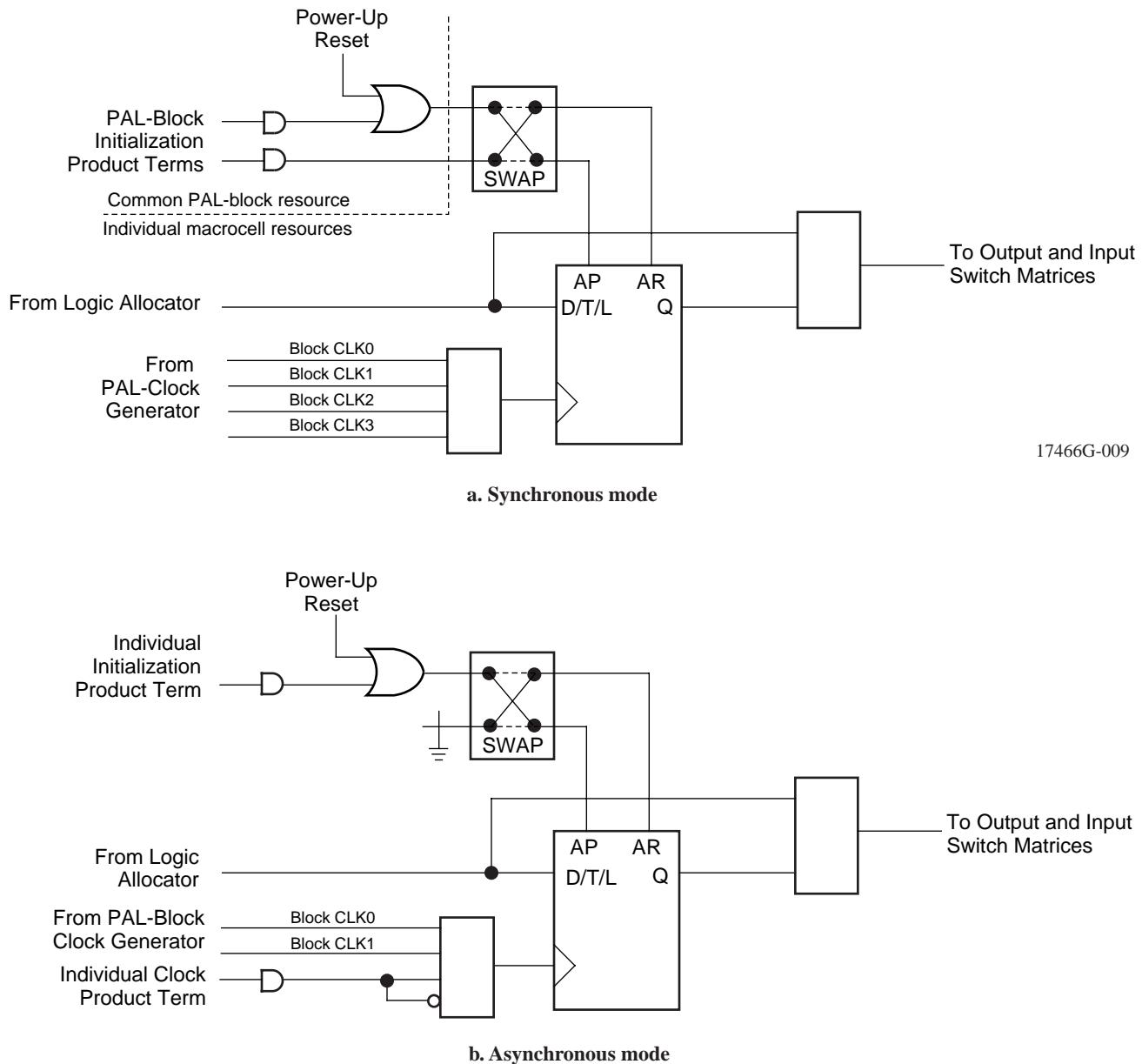
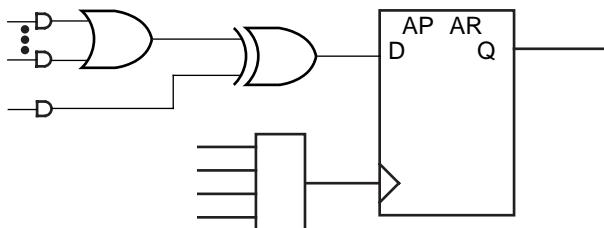


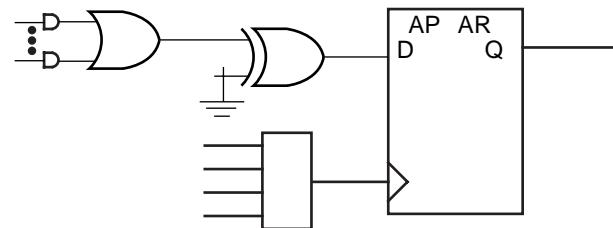
Figure 5. Macrocell

In either mode, a combinatorial path can be used. For combinatorial logic, the synchronous mode will generally be used, since it provides more product terms in the allocator.

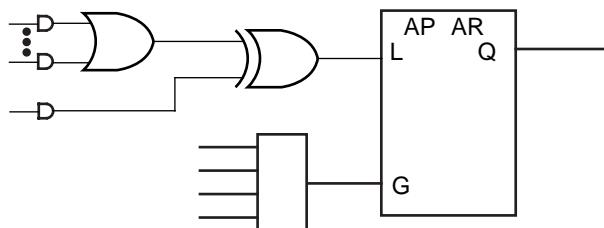
The flip-flop can be configured as a D-type or T-type latch. J-K or S-R registers can be synthesized. The primary flip-flop configurations are shown in Figure 6, although others are possible. Flip-flop functionality is defined in Table 8. Note that a J-K latch is inadvisable as it will cause oscillation if both J and K inputs are HIGH.



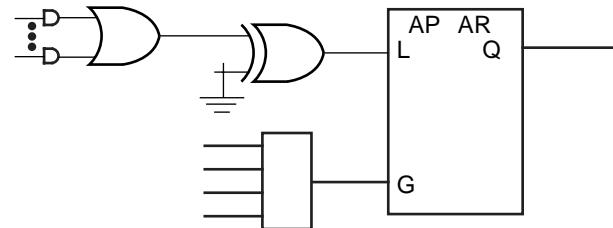
a. D-type with XOR



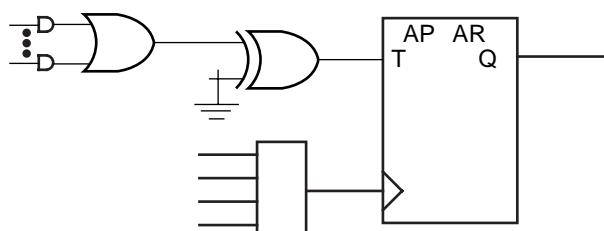
b. D-type with programmable D polarity



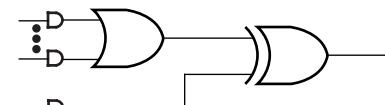
c. Latch with XOR



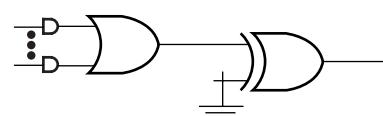
d. Latch with programmable D polarity



e. T-type with programmable T polarity



f. Combinatorial with XOR



g. Combinatorial with programmable polarity

Table 10. Output Switch Matrix Combinations for ispMACH 4A Devices with 2:1 Macrocell-I/O Cell Ratio

Macrocell	Routeable to I/O Cells
M12, M13	I/03, I/04, I/05, I/06
M14, M15	I/04, I/05, I/06, I/07

I/O Cell	Available Macrocells
I/00	M0, M1, M2, M3, M4, M5, M6, M7
I/01	M2, M3, M4, M5, M6, M7, M8, M9
I/02	M4, M5, M6, M7, M8, M9, M10, M11
I/03	M6, M7, M8, M9, M10, M11, M12, M13
I/04	M8, M9, M10, M11, M12, M13, M14, M15
I/05	M0, M1, M10, M11, M12, M13, M14, M15
I/06	M0, M1, M2, M3, M12, M13, M14, M15
I/07	M0, M1, M2, M3, M4, M5, M14, M15

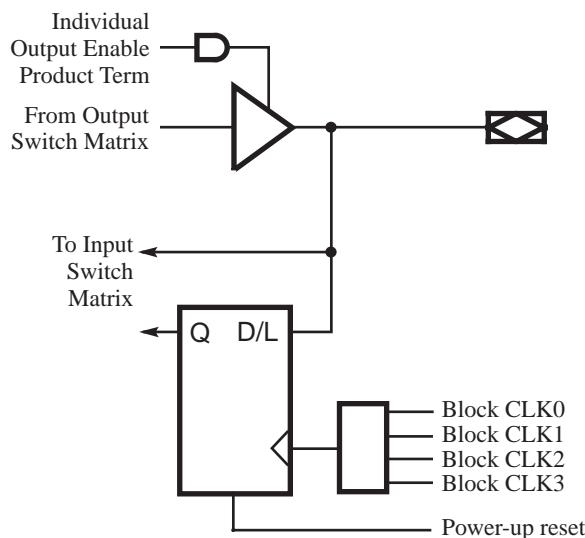
Table 11. Output Switch Matrix Combinations for M4A3-256/160 and M4A3-256/192

Macrocell	Routeable to I/O Cells							
M0	I/00	I/01	I/02	I/03	I/04	I/05	I/06	I/07
M1	I/00	I/01	I/02	I/03	I/04	I/05	I/06	I/07
M2	I/00	I/01	I/02	I/03	I/04	I/05	I/06	I/07
M3	I/00	I/01	I/02	I/03	I/04	I/05	I/06	I/07
M4	I/00	I/01	I/02	I/03	I/04	I/05	I/06	I/07
M5	I/00	I/01	I/02	I/03	I/04	I/05	I/06	I/07
M6	I/00	I/01	I/02	I/03	I/04	I/05	I/06	I/07
M7	I/00	I/01	I/02	I/03	I/04	I/05	I/06	I/07
M8	I/08	I/09	I/010	I/011	I/012	I/013	I/014	I/015
M9	I/08	I/09	I/010	I/011	I/012	I/013	I/014	I/015
M10	I/08	I/09	I/010	I/011	I/012	I/013	I/014	I/015
M11	I/08	I/09	I/010	I/011	I/012	I/013	I/014	I/015
M12	I/08	I/09	I/010	I/011	I/012	I/013	I/014	I/015
M13	I/08	I/09	I/010	I/011	I/012	I/013	I/014	I/015
M14	I/08	I/09	I/010	I/011	I/012	I/013	I/014	I/015
M15	I/08	I/09	I/010	I/011	I/012	I/013	I/014	I/015

I/O Cell	Available Macrocells							
I/00	M0	M1	M2	M3	M4	M5	M6	M7
I/01	M0	M1	M2	M3	M4	M5	M6	M7
I/02	M0	M1	M2	M3	M4	M5	M6	M7
I/03	M0	M1	M2	M3	M4	M5	M6	M7
I/04	M0	M1	M2	M3	M4	M5	M6	M7
I/05	M0	M1	M2	M3	M4	M5	M6	M7
I/06	M0	M1	M2	M3	M4	M5	M6	M7
I/07	M0	M1	M2	M3	M4	M5	M6	M7

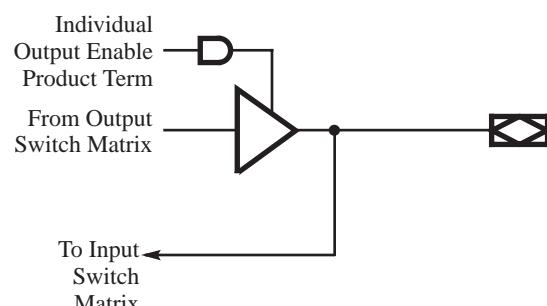
I/O Cell

The I/O cell (Figures 10 and 11) simply consists of a programmable output enable, a feedback path, and flip-flop (except ispMACH 4A devices with 1:1 macrocell-I/O cell ratio). An individual output enable product term is provided for each I/O cell. The feedback signal drives the input switch matrix.



17466G-017

Figure 10. I/O Cell for ispMACH 4A Devices with 2:1 Macrocell-I/O Cell Ratio



17466G-018

Figure 11. I/O Cell for ispMACH 4A Devices with 1:1 Macrocell-I/O Cell Ratio

The I/O cell (Figure 10) contains a flip-flop, which provides the capability for storing the input in a D-type register or latch. The clock can be any of the PAL block clocks. Both the direct and registered versions of the input are sent to the input switch matrix. This allows for such functions as “time-domain-multiplexed” data comparison, where the first data value is stored, and then the second data value is put on the I/O pin and compared with the previous stored value.

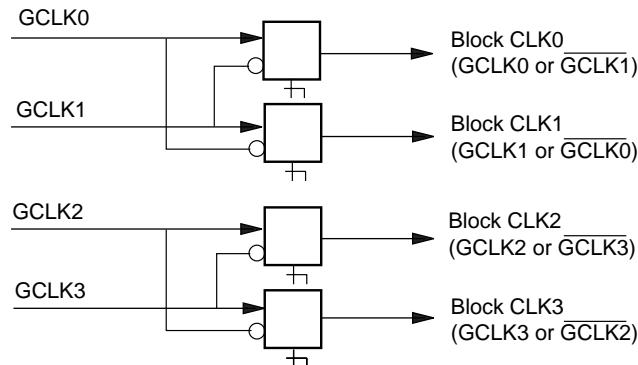
Note that the flip-flop used in the ispMACH 4A I/O cell is independent of the flip-flops in the macrocells. It powers up to a logic low.

Zero-Hold-Time Input Register

The ispMACH 4A devices have a zero-hold-time (ZHT) fuse which controls the time delay associated with loading data into all I/O cell registers and latches. When programmed, the ZHT fuse increases the data path setup delays to input storage elements, matching equivalent delays in the clock path. When the fuse is erased, the setup time to the input storage element is minimized. This feature facilitates doing worst-case designs for which data is loaded from sources which have low (or zero) minimum output propagation delays from clock edges.

PAL Block Clock Generation

Each ispMACH 4A device has four clock pins that can also be used as inputs. These pins drive a clock generator in each PAL block (Figure 14). The clock generator provides four clock signals that can be used anywhere in the PAL block. These four PAL block clock signals can consist of a large number of combinations of the true and complement edges of the global clock signals. Table 14 lists the possible combinations.



17466G-004

Figure 14. PAL Block Clock Generator¹

1. M4A(3,5)-32/32 and M4A(3,5)-64/32 have only two clock pins, GCLK0 and GCLK1. GCLK2 is tied to GCLK0, and GCLK3 is tied to GCLK1.

Table 14. PAL Block Clock Combinations¹

Block CLK0	Block CLK1	Block CLK2	Block CLK3
GCLK0	GCLK1	X	X
<u>GCLK1</u>	GCLK1	X	X
GCLK0	<u>GCLK0</u>	X	X
<u>GCLK1</u>	<u>GCLK0</u>	X	X
X	X	GCLK2 (GCLK0)	GCLK3 (GCLK1)
X	X	<u>GCLK3 (GCLK1)</u>	GCLK3 (GCLK1)
X	X	GCLK2 (GCLK0)	<u>GCLK2 (GCLK0)</u>
X	X	<u>GCLK3 (GCLK1)</u>	GCLK2 (GCLK0)

Note:

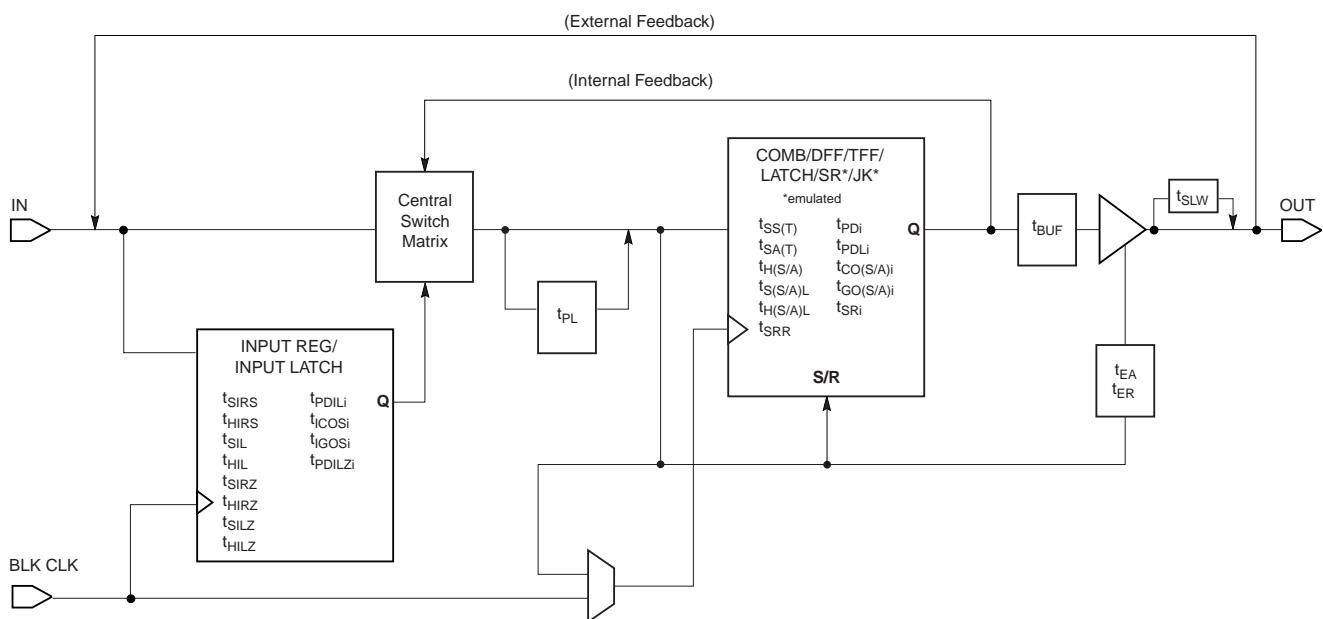
1. Values in parentheses are for the M4A(3,5)-32/32 and M4A(3,5)-64/32.

This feature provides high flexibility for partitioning state machines and dual-phase clocks. It also allows latches to be driven with either polarity of latch enable, and in a master-slave configuration.

ispMACH 4A TIMING MODEL

The primary focus of the ispMACH 4A timing model is to accurately represent the timing in a ispMACH 4A device, and at the same time, be easy to understand. This model accurately describes all combinatorial and registered paths through the device, making a distinction between internal feedback and external feedback. A signal uses internal feedback when it is fed back into the switch matrix or block without having to go through the output buffer. The input register specifications are also reported as internal feedback. When a signal is fed back into the switch matrix after having gone through the output buffer, it is using external feedback.

The parameter, t_{BUF} , is defined as the time it takes to go from feedback through the output buffer to the I/O pad. If a signal goes to the internal feedback rather than to the I/O pad, the parameter designator is followed by an “i”. By adding t_{BUF} to this internal parameter, the external parameter is derived. For example, $t_{PD} = t_{PDI} + t_{BUF}$. A diagram representing the modularized ispMACH 4A timing model is shown in Figure 15. Refer to the application note entitled *MACH 4 Timing and High Speed Design* for a more detailed discussion about the timing parameters.



17466G-025

Figure 15. ispMACH 4A Timing Model

SPEEDLOCKING FOR GUARANTEED FIXED TIMING

The ispMACH 4A architecture allows allocation of up to 20 product terms to an individual macrocell with the assistance of an XOR gate without incurring additional timing delays.

The design of the switch matrix and PAL blocks guarantee a fixed pin-to-pin delay that is independent of the logic required by the design. Other competitive CPLDs incur serious timing delays as product terms expand beyond their typical 4 or 5 product term limits. Speed and SpeedLocking combine to give designs easy access to the performance required in today's designs.

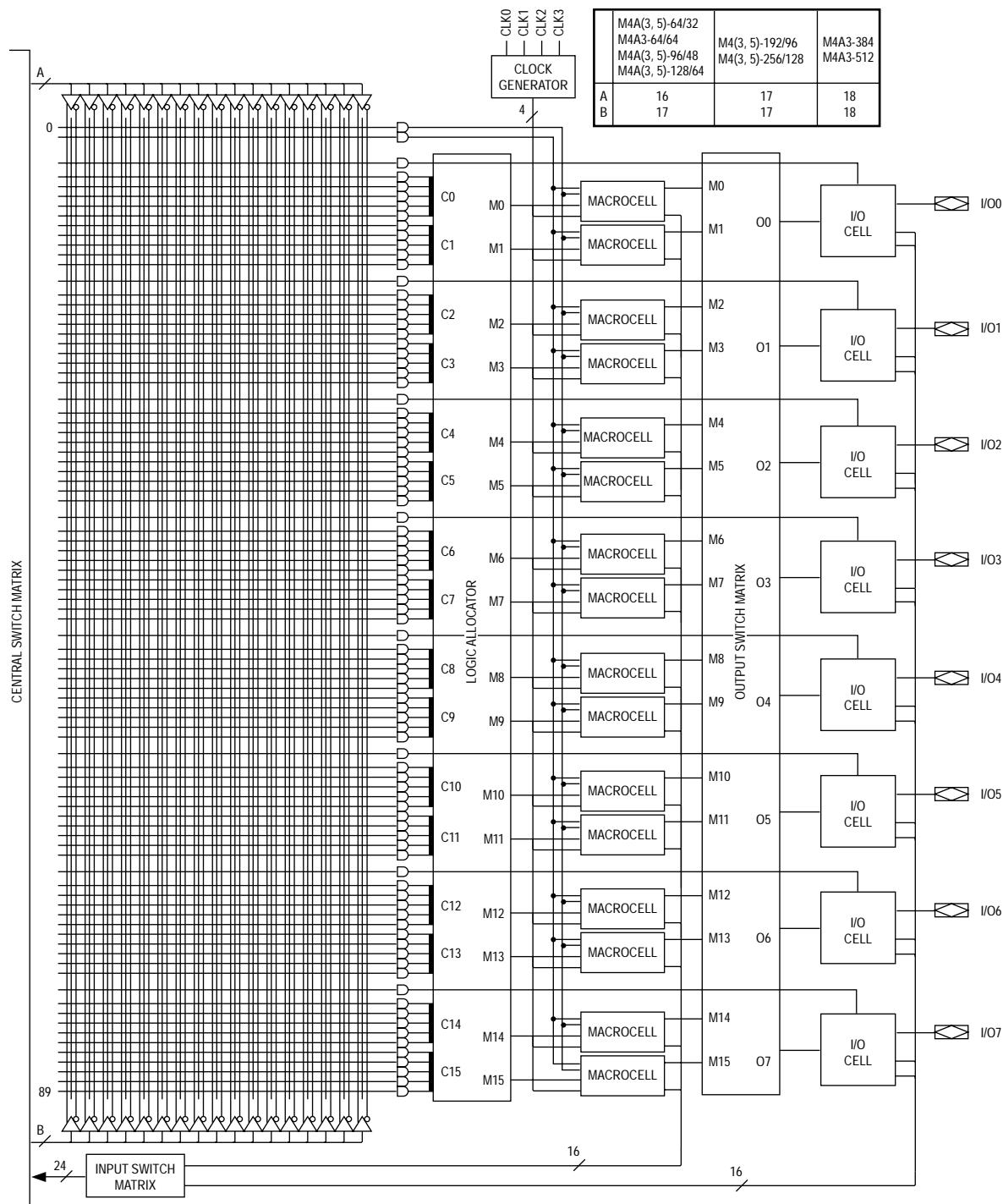
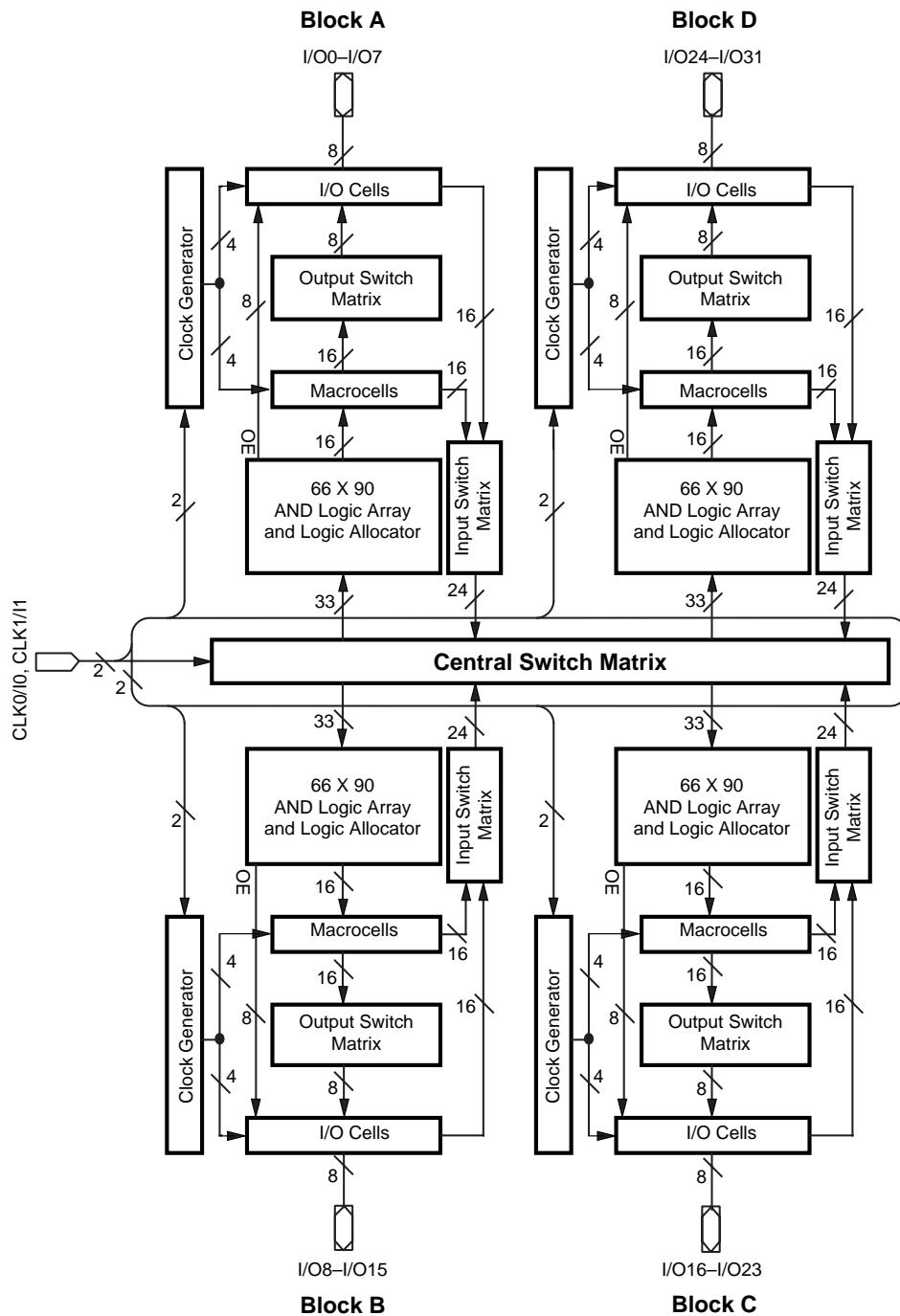
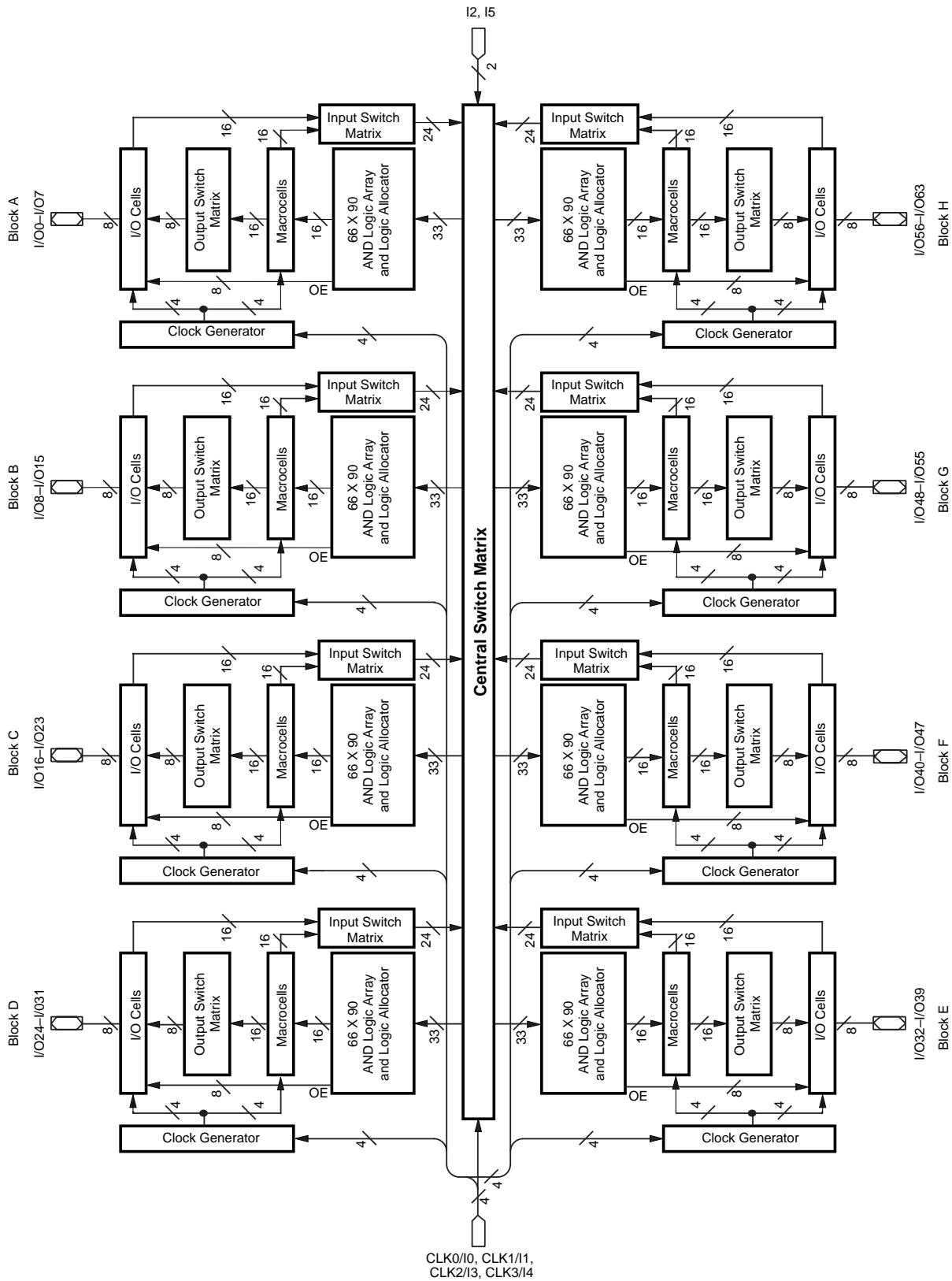


Figure 16. PAL Block for ispMACH 4A with 2:1 Macrocell - I/O Cell Ratio

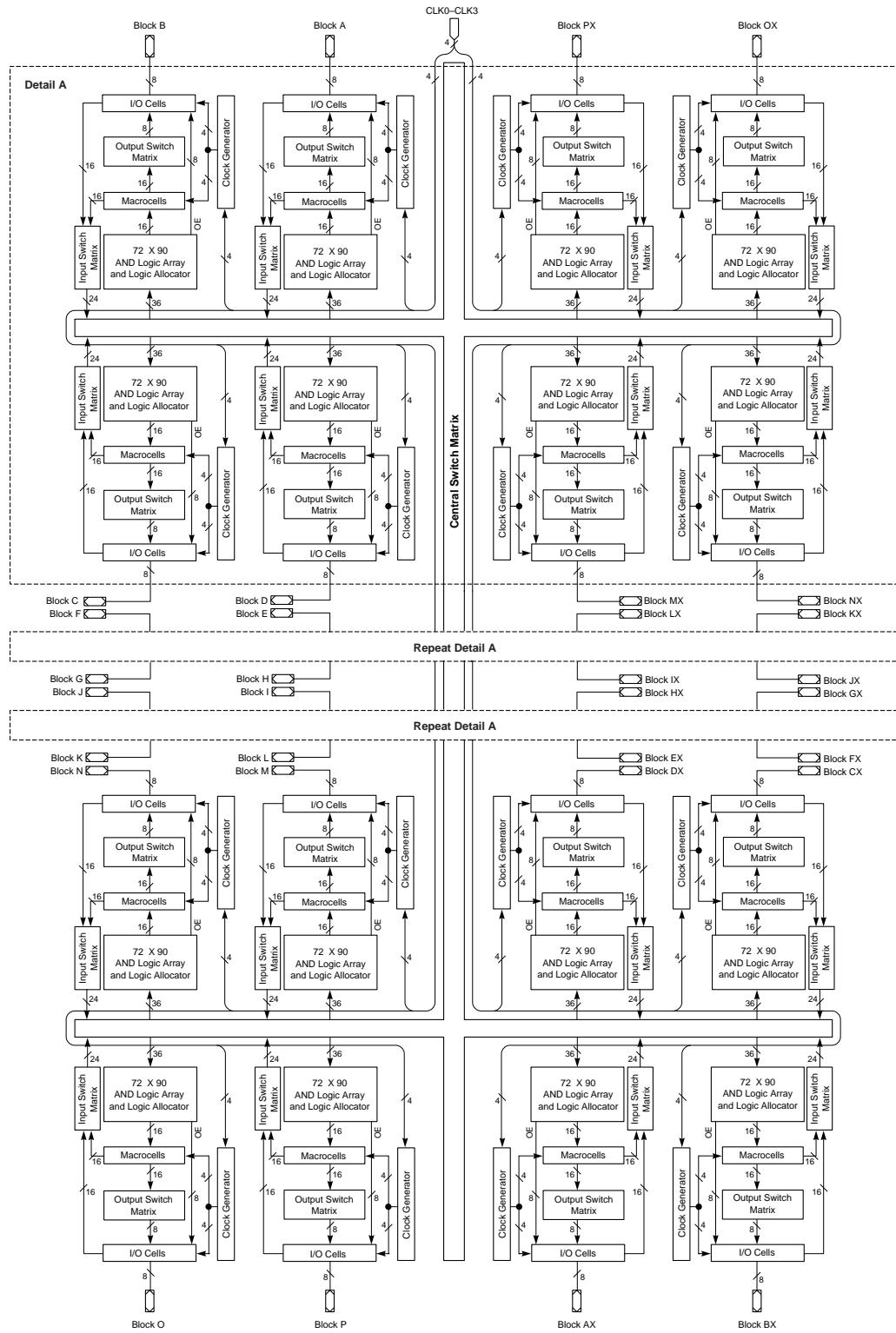
BLOCK DIAGRAM – M4A(3,5)-64/32



BLOCK DIAGRAM – M4A(3,5)-128/64



BLOCK DIAGRAM - M4A3-512/160, M4A3-512/192, M4A3-512/256



17466G-068

ABSOLUTE MAXIMUM RATINGS

M4A5

Storage Temperature.....	-65°C to +150°C
Ambient Temperature with Power Applied.....	-55°C to +100°C
Device Junction Temperature.....	+130°C
Supply Voltage with Respect to Ground	-0.5 V to +7.0 V
DC Input Voltage	-0.5 V to V_{CC} + 0.5 V
Static Discharge Voltage.....	2000 V
Latchup Current ($T_A = -40^\circ\text{C}$ to $+85^\circ\text{C}$)	200 mA
<i>Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to Absolute Maximum Ratings for extended periods may affect device reliability.</i>	

OPERATING RANGES

Commercial (C) Devices

Ambient Temperature (T_A)	
Operating in Free Air.....	0°C to +70°C
Supply Voltage (V_{CC}) with Respect to Ground.....	+4.75 V to +5.25 V

Industrial (I) Devices

Ambient Temperature (T_A)	
Operating in Free Air.....	-40°C to +85°C
Supply Voltage (V_{CC}) with Respect to Ground.....	+4.50 V to +5.5 V
<i>Operating ranges define those limits between which the functionality of the device is guaranteed.</i>	

5-V DC CHARACTERISTICS OVER OPERATING RANGES

Parameter Symbol	Parameter Description	Test Conditions	Min	Typ	Max	Unit
V_{OH}	Output HIGH Voltage	$I_{OH} = -3.2 \text{ mA}$, $V_{CC} = \text{Min}$, $V_{IN} = V_{IH}$ or V_{IL}	2.4			V
		$I_{OH} = -100 \mu\text{A}$, $V_{CC} = \text{Max}$, $V_{IN} = V_{IH}$ or V_{IL}		3.3	3.6	V
V_{OL}	Output LOW Voltage	$I_{OL} = 24 \text{ mA}$, $V_{CC} = \text{Min}$, $V_{IN} = V_{IH}$ or V_{IL} (Note 1)			0.5	V
V_{IH}	Input HIGH Voltage	Guaranteed Input Logical HIGH Voltage for all Inputs (Note 2)	2.0			V
V_{IL}	Input LOW Voltage	Guaranteed Input Logical LOW Voltage for all Inputs (Note 2)			0.8	V
I_{IH}	Input HIGH Leakage Current	$V_{IN} = 5.25 \text{ V}$, $V_{CC} = \text{Max}$ (Note 3)			10	μA
I_{IL}	Input LOW Leakage Current	$V_{IN} = 0 \text{ V}$, $V_{CC} = \text{Max}$ (Note 3)			-10	μA
I_{OZH}	Off-State Output Leakage Current HIGH	$V_{OUT} = 5.25 \text{ V}$, $V_{CC} = \text{Max}$, $V_{IN} = V_{IH}$ or V_{IL} (Note 3)			10	μA
I_{OZL}	Off-State Output Leakage Current LOW	$V_{OUT} = 0 \text{ V}$, $V_{CC} = \text{Max}$, $V_{IN} = V_{IH}$ or V_{IL} (Note 3)			-10	μA
I_{SC}	Output Short-Circuit Current	$V_{OUT} = 0.5 \text{ V}$, $V_{CC} = \text{Max}$ (Note 4)	-30		-160	mA

Notes:

1. Total I_{OL} for one PAL block should not exceed 64 mA.
2. These are absolute values with respect to device ground, and all overshoots due to system or tester noise are included.
3. I/O pin leakage is the worst case of I_{IL} and I_{OZL} (or I_{IH} and I_{OZH}).
4. Not more than one output should be shorted at a time and duration of the short-circuit should not exceed one second. $V_{OUT} = 0.5 \text{ V}$ has been chosen to avoid test problems caused by tester ground degradation.

ispMACH 4A TIMING PARAMETERS OVER OPERATING RANGES¹

		-5		-55		-6		-65		-7		-10		-12		-14		Unit
		Min	Max	Min	Max	Min	Max	Min	Max									
Combinatorial Delay:																		
t _{PDI}	Internal combinatorial propagation delay		3.5		4.0		4.3		4.5		5.0		7.0		9.0		11.0	ns
t _{PD}	Combinatorial propagation delay		5.0		5.5		6.0		6.5		7.5		10.0		12.0		14.0	ns
Registered Delays:																		
t _{SS}	Synchronous clock setup time, D-type register	3.0		3.5		3.5		3.5		5.0		5.5		7.0		10.0		ns
t _{SST}	Synchronous clock setup time, T-type register	4.0		4.0		4.0		4.0		6.0		6.5		8.0		11.0		ns
t _{SA}	Asynchronous clock setup time, D-type register	2.5		2.5		2.5		3.0		3.5		4.0		5.0		8.0		ns
t _{SAT}	Asynchronous clock setup time, T-type register	3.0		3.0		3.0		3.5		4.5		5.0		6.0		9.0		ns
t _{HS}	Synchronous clock hold time	0.0		0.0		0.0		0.0		0.0		0.0		0.0		0.0		ns
t _{HA}	Asynchronous clock hold time	2.5		2.5		2.5		3.0		3.5		4.0		5.0		8.0		ns
t _{COSI}	Synchronous clock to internal output		2.5		2.5		2.8		3.0		3.0		3.0		3.5		3.5	ns
t _{COS}	Synchronous clock to output		4.0		4.0		4.5		5.0		5.5		6.0		6.5		6.5	ns
t _{COAi}	Asynchronous clock to internal output		5.0		5.0		5.0		5.0		6.0		8.0		10.0		12.0	ns
t _{COA}	Asynchronous clock to output		6.5		6.5		6.8		7.0		8.5		11.0		13.0		15.0	ns
Latched Delays:																		
t _{SSL}	Synchronous latch setup time	4.0		4.0		4.0		4.5		6.0		7.0		8.0		10.0		ns
t _{SAL}	Asynchronous latch setup time	3.0		3.0		3.5		3.5		4.0		4.0		5.0		8.0		ns
t _{HSL}	Synchronous latch hold time	0.0		0.0		0.0		0.0		0.0		0.0		0.0		0.0		ns
t _{HAL}	Asynchronous latch hold time	3.0		3.0		3.5		3.5		4.0		4.0		5.0		8.0		ns
t _{PDLi}	Transparent latch to internal output		5.5		5.5		5.8		6.0		7.5		9.0		11.0		12.0	ns
t _{PDL}	Propagation delay through transparent latch to output		7.0		7.0		7.5		8.0		10.0		12.0		14.0		15.0	ns
t _{GOSI}	Synchronous gate to internal output		3.0		3.0		3.0		3.0		3.5		4.5		7.0		8.0	ns
t _{GOS}	Synchronous gate to output		4.5		4.5		4.8		5.0		6.0		7.5		10.0		11.0	ns
t _{GOAi}	Asynchronous gate to internal output		6.0		6.0		6.0		6.0		8.5		10.0		13.0		15.0	ns
t _{GOA}	Asynchronous gate to output		7.5		7.5		7.8		8.0		11.0		13.0		16.0		18.0	ns
Input Register Delays:																		
t _{SIRS}	Input register setup time	1.5		1.5		2.0		2.0		2.0		2.0		2.0		2.0		ns
t _{HIRS}	Input register hold time	2.5		2.5		3.0		3.0		3.0		3.0		3.0		4.0		ns
t _{ICOSI}	Input register clock to internal feedback		3.0		3.0		3.0		3.0		3.5		4.5		6.0		6.0	ns
Input Latch Delays:																		
t _{SIL}	Input latch setup time	1.5		1.5		1.5		2.0		2.0		2.0		2.0		2.0		ns
t _{HIL}	Input latch hold time	2.5		2.5		2.5		3.0		3.0		3.0		3.0		4.0		ns
t _{IGOSI}	Input latch gate to internal feedback		3.5		3.5		3.8		4.0		4.0		4.0		4.0		5.0	ns
t _{PDILI}	Transparent input latch to internal feedback		1.5		1.5		1.5		1.5		2.0		2.0		2.0		2.0	ns

I_{CC} vs. FREQUENCY

These curves represent the typical power consumption for a particular device at system frequency. The selected “typical” pattern is a 16-bit up-down counter. This pattern fills the device and exercises every macrocell. Maximum frequency shown uses internal feedback and a D-type register. Power-Speed are optimized to obtain the highest counter frequency and the lowest power. The highest frequency (LSBs) is placed in common PAL blocks, which are set to high power. The lowest frequency signals (MSBs) are placed in a common PAL block and set to lowest power.

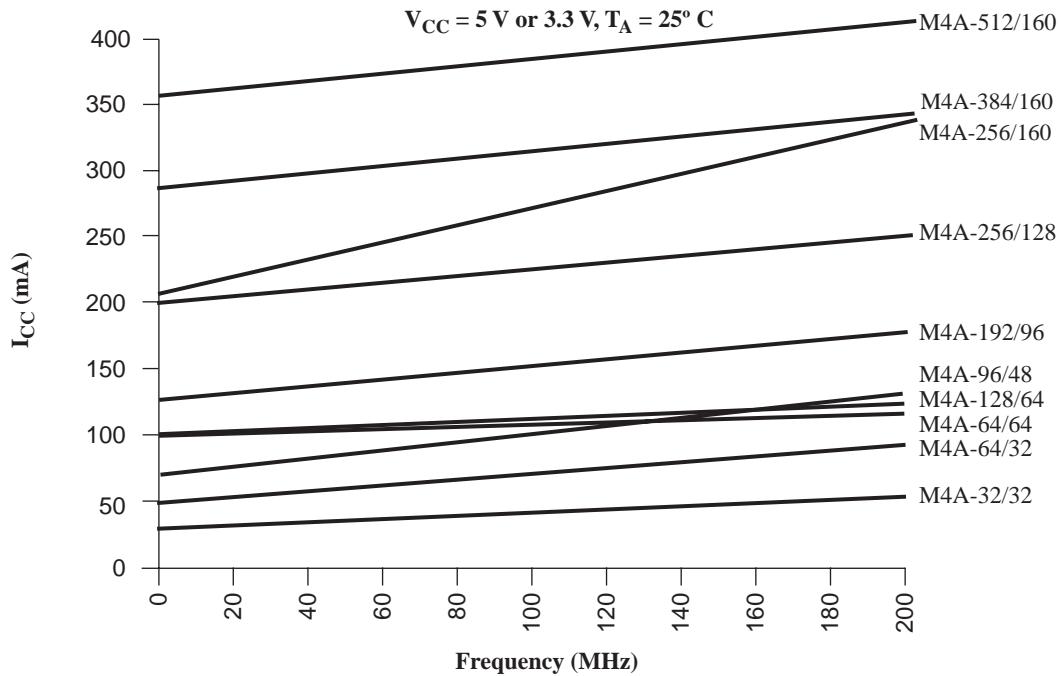


Figure 19. ispMACH 4A I_{CC} Curves at High Speed Mode

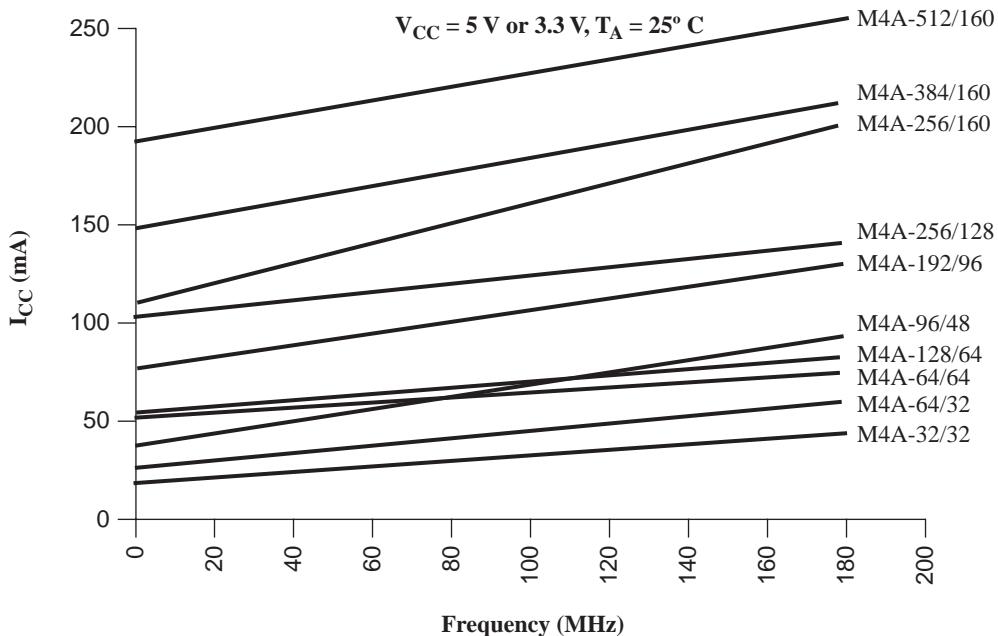
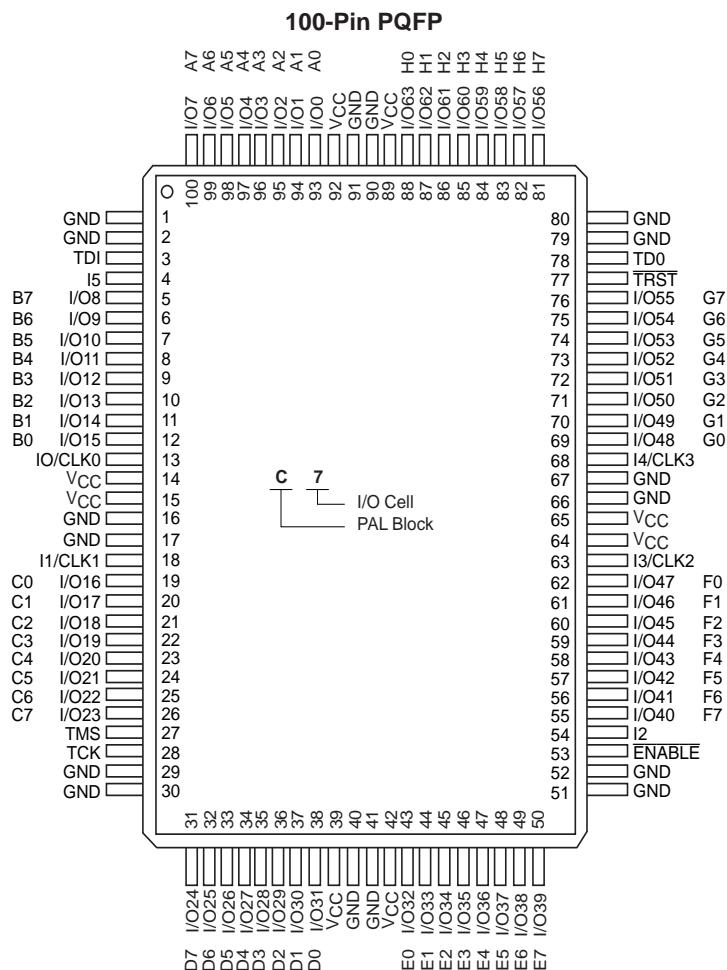


Figure 20. ispMACH 4A I_{CC} Curves at Low Power Mode

100-PIN PQFP CONNECTION DIAGRAM (M4A(3,5)-128/64)

Top View



PIN DESIGNATIONS

I/CLK = Input or Clock

GND = Ground

I = Input

I/O = Input/Output

V_{CC} = Supply Voltage

TDI = Test Data In

TCK = Test Clock

TMS = Test Mode Select

TDO = Test Data Out

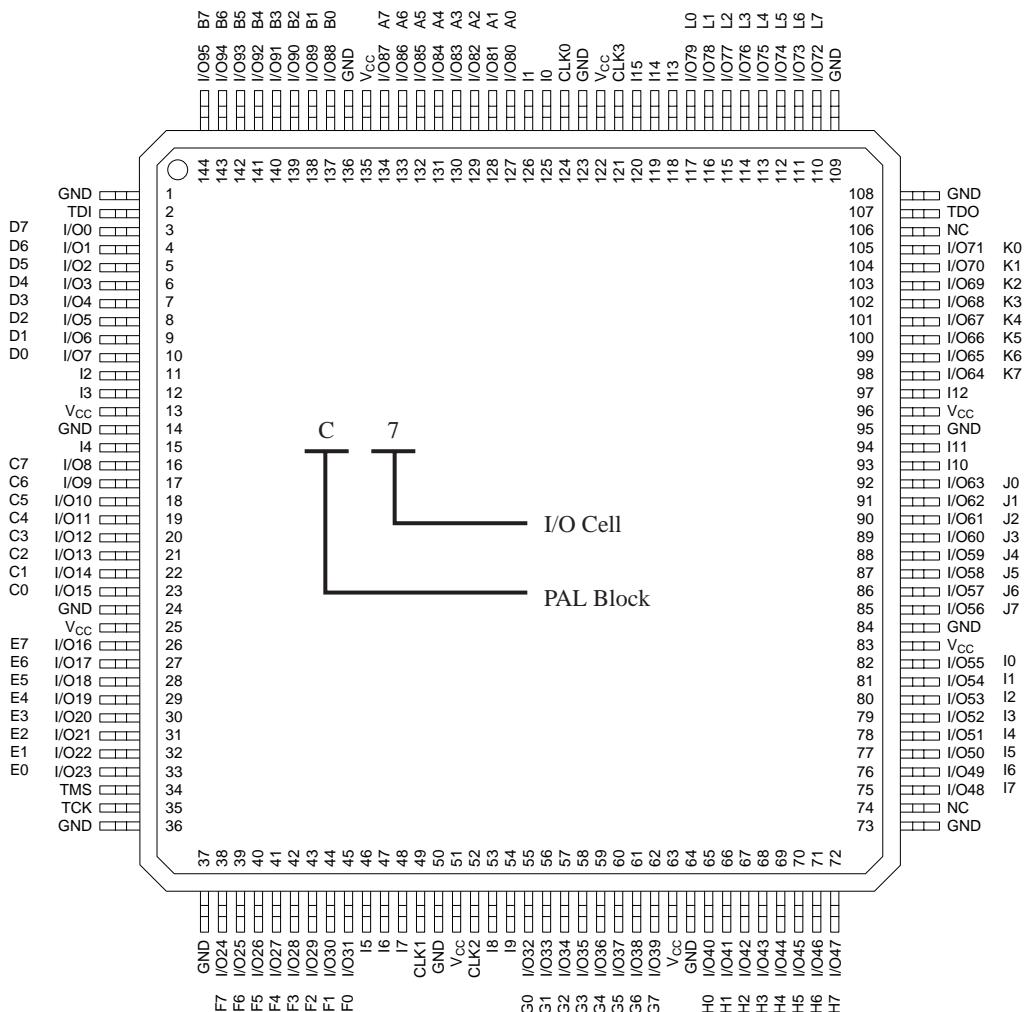
TRST = Test Reset

ENABLE = Program

144-PIN TQFP CONNECTION DIAGRAM (M4A(3,5)-192/96)

Top View

144-Pin TQFP



17466G-033

PIN DESIGNATIONS

- CLK = Clock
- GND = Ground
- I = Input
- I/O = Input/Output
- V_{CC} = Supply Voltage
- TDI = Test Data In
- TCK = Test Clock
- TMS = Test Mode Select
- TDO = Test Data Out

144-BALL FPBGA CONNECTION DIAGRAM (M4A3-192/96)

Bottom View

144-Ball fpBGA

	12	11	10	9	8	7	6	5	4	3	2	1	
A	GND	I/O72 L7	I/O76 L3	I13	GBCLK3	I0	I/O82 A2	I/O86 A6	I/O88 B0	I/O93 B5	I/O95 B7	GND	A
B	GND	I/O73 L6	I/O77 L2	I/O79 L0	VCC	I1	I/O83 A3	I/O87 A7	I/O90 B2	I/O94 B6	I/O0 D7	TDI	B
C	GND	TDO	I/O74 L5	I14	GND	I/O80 A0	I/O84 A4	GND	I/O92 B4	I/O1 D6	I/O4 D3	I/O3 D4	C
D	I/O67 K4	I/O69 K2	I/O71 K0	I/O75 L4	GBCLK0	I/O81 A1	VCC	I/O91 B3	I/O2 D5	I2	I/O6 D1	I/O7 D0	D
E	I12	I/O64 K7	I/O66 K5	I/O70 K1	I/O78 L1	I/O85 A5	I/O89 B1	I/O5 D2	I/O8 C7	I4	GND	VCC	E
F	I10	I11	GND	I/O65 K6	I/O68 K3	I15	I3	GND	I/O12 C3	I/O11 C4	I/O10 C5	I/O9 C6	F
G	I/O60 J3	I/O61 J2	I/O62 J1	I/O63 J0	VCC	GND	I7	I/O20 E3	I/O17 E6	I/O15 C0	I/O14 C1	I/O13 C2	G
H	I/O56 J7	I/O57 J6	I/O58 J5	I/O59 J4	I/O53 I2	I/O41 H1	I/O37 G5	I/O30 F1	I/O22 E1	I/O18 E5	I/O16 E7	VCC	H
J	I/O55 I0	I/O54 I1	VCC	I/O50 I5	I/O43 H3	VCC	I/O33 G1	GBCLK2	I/O27 F4	I/O23 E0	I/O21 E2	I/O19 E4	J
K	I/O51 I4	I/O52 I3	I/O49 I6	I/O44 H4	GND	I/O36 G4	I/O32 G0	VCC	I6	I/O26 F5	TCK	TMS	K
L	GND	I/O48 I7	I/O46 H6	I/O42 H2	I/O39 G7	I/O35 G3	I9	GND	I/O31 F0	I/O29 F2	I/O25 F6	GND	L
M	GND	I/O47 H7	I/O45 H5	I/O40 H0	I/O38 G6	I/O34 G2	I8	GBCLK1	I5	I/O28 F3	I/O24 F7	GND	M

PIN DESIGNATIONS

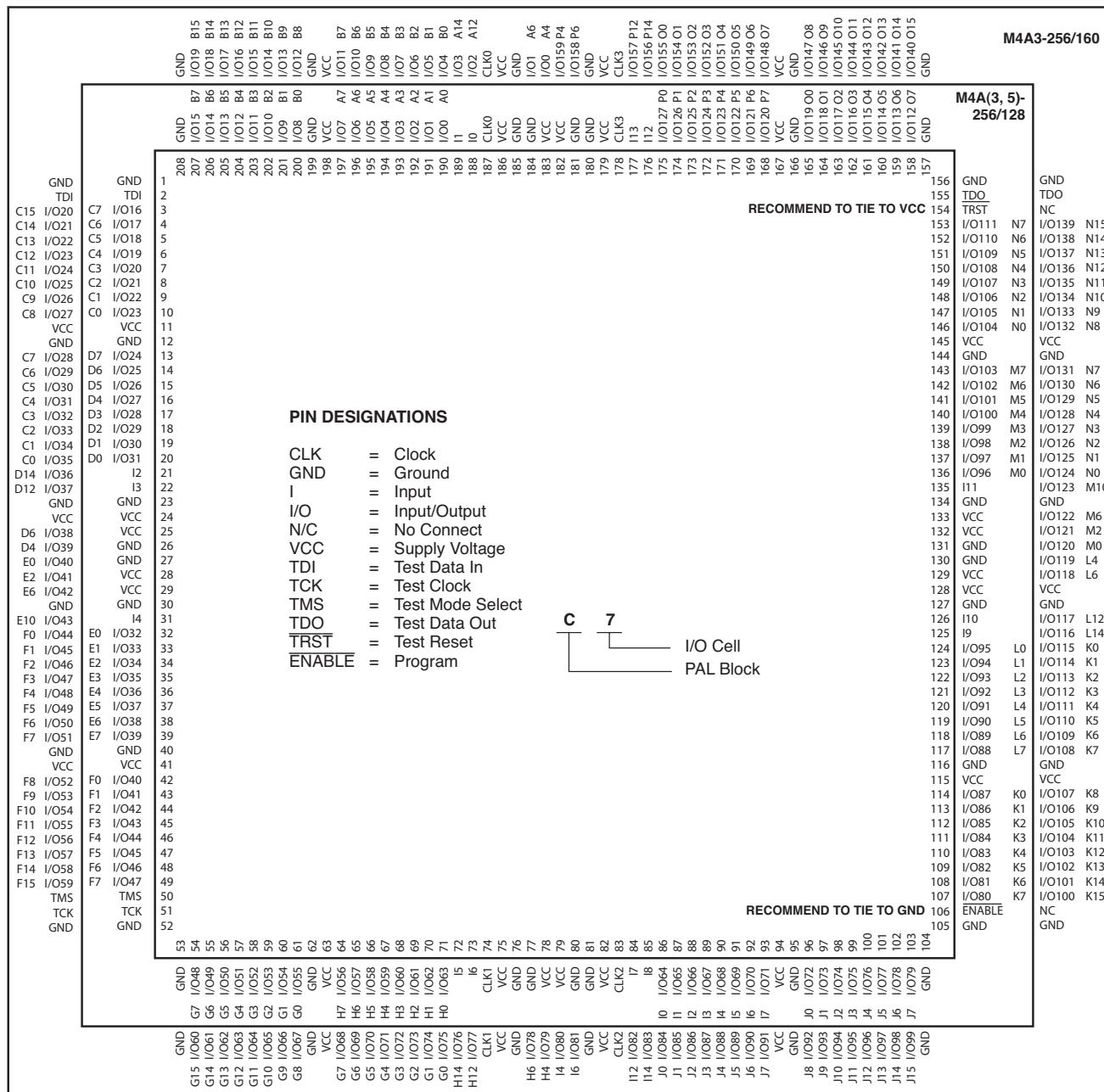
CLK = Clock
 GND = Ground
 I = Input
 I/O = Input/Output
 N/C = No Connect
 VCC = Supply Voltage
 TDI = Test Data In
 TCK = Test Clock
 TMS = Test Mode Select
 TDO = Test Data Out



208-PIN PQFP CONNECTION DIAGRAM (M4A(3,5)-256/128 AND M4A3-256/160)

Top View

208-Pin PQFP



17466G-044

256-BALL fpBGA CONNECTION DIAGRAM (M4A3-256/128)

Bottom View

256-Ball fpBGA

	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	
A	TRST	I/O117 O5	I/O116 O4	I/O113 O1	I/O126 P6	I/O124 P4	I12	NC	NC	NC	CLK0	I/O1 A1	I/O5 A5	I/O7 A7	I/O10 B2	I/O12 B4 <th>A</th>	A
B	I/O110 N6	I/O111 N7	I/O118 O6	I/O115 O3	I/O127 P7	I/O125 P5	I/O120 P0	NC	NC	NC	I1	I/O2 A2	I/O8 B0	I/O11 B3	I/O13 B5	NC	B
C	I/O108 N4	I/O109 N5	NC	I/O119 O7	I/O114 O2	I/O122 P2	I/O123 P3	NC	NC	I0	I/O4 A4	I/O6 A6	I/O15 B7	I/O14 B6	TDI	I/O23 C7	C
D	NC	I/O104 N0	TDO	GND	GND	VCC	GND	VCC	GND	GND	VCC	GND	VCC	I/O9 B1	I/O22 C6	I/O21 C5	D
E	I/O102 M6	NC	I/O107 N3	VCC	I/O105 N1	I/O106 N2	I13	CLK3	NC	NC	I/O0 A0	NC	GND	I/O20 C4	I/O19 C3	I/O31 D7	E
F	I/O98 M2	I/O103 M7	I/O101 M5	GND	I/O100 M4	I/O99 M3	I/O112 O0	I/O121 P1	NC	NC	I/O3 A3	I/O18 C2	VCC	I/O16 C0	I/O30 D6	I/O29 D5	F
G	NC	I/O96 M0	I11	VCC	NC	I/O97 M1	VCC	GND	VCC	I/O17 C1	I/O28 D4	GND	I/O26 D2	I/O25 D1	I2	G	
H	I/O88 L0	I10	I9	GND	I/O89 L1	I/O90 L2	GND	VCC	VCC	GND	I/O27 D3	I/O24 D0	VCC	NC	NC	NC	H
J	I/O91 L3	I/O92 L4	I/O93 L5	GND	I/O95 L7	I/O94 L6	GND	VCC	VCC	GND	I3	NC	GND	NC	NC	NC	J
K	NC	NC	NC	VCC	NC	NC	VCC	GND	GND	VCC	NC	NC	VCC	I4	NC	I/O32 E0	K
L	NC	NC	I/O80 K0	GND	I/O83 K3	NC	NC	NC	I/O59 H3	I/O61 H5	NC	NC	GND	I/O35 E3	I/O36 E4	I/O33 E1	L
M	I/O81 K1	I/O82 K2	I/O84 K4	GND	I/O67 I3	I/O65 I1	NC	NC	I/O58 H2	I/O48 G0	I/O51 G3	NC	VCC	I/O44 F4	I/O39 E7	I/O34 E2	M
N	I/O85 K5	I/O86 K6	ENABLE	VCC	GND	VCC	GND	VCC	GND	GND	VCC	GND	GND	TCK	I/O40 F0	I/O37 E5	N
P	I/O87 K7	I/O77 J5	I/O78 J6	I/O79 J7	I/O68 I4	I/O66 I2	NC	NC	NC	I6	I/O63 H7	I/O52 G4	I/O55 G7	TMS	I/O41 F1	I/O38 E6	P
R	I/O76 J4	I/O75 J3	I/O72 J0	I/O71 I7	I/O64 I0	I7	NC	NC	NC	I/O56 H0	I/O60 H4	I/O49 G1	I/O53 G5	I/O47 F7	I/O43 F3	I/O42 F2	R
T	I/O74 J2	I/O73 J1	I/O70 I6	I/O69 I5	I8	CLK2	NC	NC	CLK1	I5	I/O57 H1	I/O62 H6	I/O50 G2	I/O54 G6	I/O46 F6	I/O45 F5	T
	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	

PIN DESIGNATIONS

CLK = Clock
 GND = Ground
 I = Input
 I/O = Input/Output
 N/C = No Connect
 VCC = Supply Voltage
 TDI = Test Data In
 TCK = Test Clock
 TMS = Test Mode Select
 TDO = Test Data Out
 TRST = Test Reset
 ENABLE = Program



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388-BALL fpBGA CONNECTION DIAGRAM (M4A3-512/256)

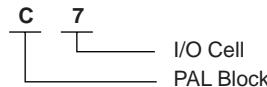
Bottom View

388-Ball fpBGA

	22	21	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	
A	GND	I/O243 OX3	I/O240 OX0	I/O241 OX1	I/O236 NX4	I/O231 MX7	I/O228 MX4	I/O226 MX2	I/O255 PX7	I/O251 PX3	I/O248 PX0	I/O0 A0	I/O5 A5	I/O6 A6	I/O27 D3	I/O30 D6	I/O17 C1	I/O22 C6	I/O8 B0	I/O10 B2	N/C	GND	A
B	N/C	GND	I/O245 OX5	I/O242 OX2	I/O238 NX6	I/O234 NX2	I/O232 NX0	I/O229 MX5	I/O224 MX0	I/O253 PX5	I/O249 PX1	I/O2 A2	CLK0	I/O26 D2	I/O29 D5	I/O31 D7	I/O20 C4	I/O9 B1	I/O12 B4	I/O13 B5	GND	TDI	B
C	I/O213 KX5	TDO	GND	I/O247 OX7	I/O244 OX4	I/O239 NX7	I/O235 NX3	I/O230 MX6	I/O227 MX3	CLK3	I/O250 PX2	I/O1 A1	I/O7 A7	I/O25 D1	I/O16 C0	I/O18 C2	I/O23 C7	I/O11 B3	I/O15 B7	GND	I/O47 F7	I/O44 F4	C
D	I/O210 KX2	I/O212 KX4	I/O215 KX7	GND	I/O246 OX6	VCC	I/O237 NX5	I/O233 NX1	VCC	I/O254 PX6	VCC	I/O3 A3	I/O24 D0	VCC	I/O19 C3	I/O21 C5	VCC	I/O14 B6	GND	I/O46 F6	I/O43 F3	I/O41 F1	D
E	I/O207 JX7	I/O209 KX1	I/O211 KX3	I/O214 KX6															I/O45 F5	I/O42 F2	I/O40 F0	I/O54 G6	E
F	I/O203 JX3	I/O205 JX5	I/O208 KX0	VCC															VCC	I/O55 G7	I/O52 G4	I/O50 G2	F
G	I/O200 JX0	I/O202 JX2	I/O204 JX4	I/O206 JX6			VCC	VCC	N/C	I/O225 MX1	I/O252 PX4	I/O4 A4	I/O28 D4	N/C	VCC	VCC			I/O53 G5	I/O51 G3	I/O49 G1	I/O39 E7	G
H	I/O221 LX5	I/O222 LX6	I/O223 LX7	I/O201 JX1			VCC	N/C	GND	GND	GND	GND	GND	GND	N/C	VCC			I/O48 G0	I/O38 E6	I/O37 E5	I/O36 E4	H
J	I/O218 LX2	I/O219 LX3	I/O220 LX4	VCC			N/C	GND	GND	GND	GND	GND	GND	GND	N/C	VCC			VCC	I/O35 E3	I/O34 E2	I/O32 E0	J
K	I/O197 IX5	I/O198 IX6	I/O199 IX7	I/O216 LX0			I/O217 LX1	GND	GND	GND	GND	GND	GND	GND	I/O33 E1				I/O63 H7	I/O62 H6	I/O61 H5	I/O60 H4	K
L	I/O192 IX0	I/O194 IX2	I/O195 IX3	I/O196 IX4			I/O193 IX1	GND	GND	GND	GND	GND	GND	GND	I/O58 H2				VCC	I/O59 H3	I/O57 H1	I/O56 H0	L
M	I/O184 HX0	I/O185 HX1	I/O187 HX3	VCC			I/O186 HX2	GND	GND	GND	GND	GND	GND	GND	I/O69 I5				I/O67 I3	I/O65 I1	I/O66 I2	I/O64 I0	M
N	I/O188 HX4	I/O189 HX5	I/O191 HX7	I/O190 HX6			I/O162 EX2	GND	GND	GND	GND	GND	GND	GND	I/O89 L1				I/O88 L0	I/O71 I7	I/O70 I6	I/O68 I4	N
P	I/O160 EX0	I/O161 EX1	I/O163 EX3	VCC			N/C	GND	GND	GND	GND	GND	GND	GND	N/C				VCC	I/O92 L4	I/O91 L3	I/O90 L2	P
R	I/O164 EX4	I/O165 EX5	I/O166 EX6	I/O177 GX1			VCC	N/C	GND	GND	GND	GND	GND	GND	N/C	VCC			I/O74 J2	I/O95 L7	I/O94 L6	I/O93 L5	R
T	I/O167 EX7	I/O176 GX0	I/O179 GX3	I/O181 GX5			VCC	VCC	N/C	I/O152 DX0	I/O131 AX3	I/O122 P2	I/O98 M2	N/C	VCC	VCC			I/O78 J6	I/O76 J4	I/O73 J1	I/O72 J0	T
U	I/O178 GX2	I/O180 GX4	I/O183 GX7	VCC															VCC	I/O80 K0	I/O77 J5	I/O75 J3	U
V	I/O182 GX6	N/C	I/O169 FX1	I/O172 FX4															I/O86 K6	I/O83 K3	I/O81 K1	I/O79 J7	V
W	I/O168 FX0	I/O170 FX2	I/O173 FX5	GND	I/O143 BX7	VCC	I/O150 CX6	I/O145 CX1	VCC	I/O153 DX1	I/O123 P3	VCC	I/O96 M0	VCC	I/O104 N0	I/O111 N7	VCC	I/O119 O7	GND	I/O87 K7	I/O84 K4	I/O82 K2	W
Y	I/O171 FX3	I/O174 FX6	GND	I/O141 BX5	I/O138 BX2	I/O136 BX0	I/O147 CX3	I/O158 DX6	I/O156 DX4	CLK2	I/O132 AX4	I/O121 P1	I/O125 P5	I/O99 M3	I/O101 M5	I/O106 N2	I/O110 N6	I/O115 O3	I/O118 O6	GND	TMS	I/O85 K5	Y
AA	I/O175 FX7	GND	I/O142 BX6	I/O140 BX4	I/O151 CX7	I/O149 CX5	I/O144 CX0	I/O157 DX5	I/O154 DX2	I/O134 AX6	I/O130 AX2	I/O128 AX0	CLK1	I/O127 P7	I/O100 M4	I/O103 M7	I/O108 N4	I/O109 N5	I/O113 O1	I/O116 O4	GND	TCK	AA
AB	GND	N/C	I/O139 BX3	I/O137 BX1	I/O148 CX4	I/O146 CX2	I/O159 DX7	I/O155 DX3	I/O135 AX7	I/O133 AX5	I/O129 AX1	I/O120 P0	I/O124 P4	I/O126 P6	I/O97 M1	I/O102 M6	I/O105 N1	I/O107 N3	I/O112 O0	I/O114 O2	I/O117 O5	GND	AB

PIN DESIGNATIONS

CLK = Clock
 GND = Ground
 I = Input
 I/O = Input/Output
 N/C = No Connect
 VCC = Supply Voltage
 TDI = Test Data In
 TCK = Test Clock
 TMS = Test Mode Select
 TDO = Test Data Out



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